

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination TAN ET AL.	
		10/720,465	Examiner	Art Unit
DUC Q. DINH		2629	Page 1 of 1	

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,172,354	01-2001	Adan et al.	250/221
*	B	US-6,496,180	12-2002	Hedman, Michael	345/166
*	C	US-6,585,158	07-2003	Norskog, Allen C.	235/462.13
*	D	US-5,608,339	03-1997	Fujiwara, Masayuu	326/27
*	E	US-5,574,480	11-1996	Pranger et al.	345/166
*	F	US-2002/0139918	10-2002	Jung et al.	250/205
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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